


<b>Search Notes</b>  	<b>Application/Control No.</b>  10573166	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  Sheela J Huff	<b>Art Unit</b>  1643

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
inventor serach on PALNM	10/21/08	sjh
SCORE- SEQ ID NO. 2 and 3	10/21/08	sjh
Stic structure search	10/21/08	sjh
WEST-insert	10/21/08	sjh
STN-inseret	10/21/08	sjh
WEST-insert	4/7/09	sjh

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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